Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/808,330	TOIZUMI ET AL.
Examiner	Art Unit
Huan H. Tran	2861

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
		,	
Interferen history_se		2/8/2006	ННТ

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (USPAT; US_PGPUB;EPO;JPO;IBM-TDB)_see search history printout	2/8/2006	ннт
347/129,130,140; 399/136,168-221 (text search only_see search history printout)	2/8/2006	ннт